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Journal of The  
Electrochemical  
Society

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A Journal for Solid-State and  
Electrochemical Science and Technology

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Volume 145, Number 7  
July 1998





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1998

**I**n June 1998, the **Journal** and The Electrochemical Society reached a point of no return. For the first time since July 1977, the **Journal** offered no rapid-publication section. We have been brought to this departure of the Letters Section after years of planning and there will be no turning back, just a single backward glance. This month, July 1998, the Letters Section becomes its own publication — *Electrochemical and Solid-State Letters*. *Letters* is the first, and only, electrochemical journal dedicated exclusively to rapid publication with a lagtime goal of eight to ten weeks to electronic publication. *Letters* is a joint publication of ECS and the Electron Devices Society (EDS) of the Institute of Electrical and Electronics Engineers (IEEE), bolstering its solid-state component. The departure of the Letters Section will bring a new emphasis to its content, facilitating growth in quality and quantity. *Letters* will be a part of the member benefits package of both ECS and EDS, giving it an initial circulation of more than 15,000 individuals and institutions, twice that of the **Journal**.

The Letters Section of the **Journal** grew out of the Accelerated Brief Communications (ABCs). In July 1977, Editor Norman Hackerman created ABCs as a short lagtime section of the **Journal**. They were printed from camera-ready copies from the authors and inserted into each issue at the end of the Technical Papers Section. In May 1991, Editor Barry Miller moved ABCs to the front of the **Journal**, had them typeset, and renamed them the Letters Section. These short papers have provided authors an opportunity to disseminate important new information in a timely manner.

After 21 years of nurturing a rapid-publication section, the **Journal** now improves upon the concept and moves forward, allowing the need for rapid publication to be better met by a new publication. Perhaps better said by Weber: "*Past all thought of 'if' or 'when' — no use resisting — abandon thought and let the dream descend...*" "*Past the point of no return, the final threshold — what... secrets will we learn beyond the point of no return?*"



**Paul Kohl**  
Editor

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The *Journal of The Electrochemical Society* (USPS 284-140) (ISSN 0013-4651) is published monthly by The Electrochemical Society, Inc., 10 South Main Street, Pennington, NJ 08534-2896, USA, at Cummings Printing Co., 4 Peters Brook Drive, PO Box 16495, Hooksett, NH 03106-6495, USA. Subscription to members is part of membership service. Annual Membership dues: \$90 for Active Members and \$10 for Student Members. Subscription to nonmembers \$500 plus \$25 for postage outside U.S. Single copies \$15 for members and \$47 for nonmembers.

Periodicals postage paid at Pennington, New Jersey, USA and at additional mailing offices. POSTMASTER: Send address changes to: The Electrochemical Society, Inc., 10 South Main Street

## Publication Information

**Address:** The mailing address for the Executive Offices, Editorial Department, and the Circulation Department of The Electrochemical Society is: 10 South Main Street, Pennington, New Jersey, 08534-2896, USA. The telephone number is (609) 737-1902. The Fax number is (609) 737-2743, and e-mail may be sent to: [ecs@electrochem.org](mailto:ecs@electrochem.org). The ECS Home Page is located at the following address on the World Wide Web: <http://www.electrochem.org>.

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